

Beam Test of Deep Diffused APDs

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on behalf of \$(see next page)

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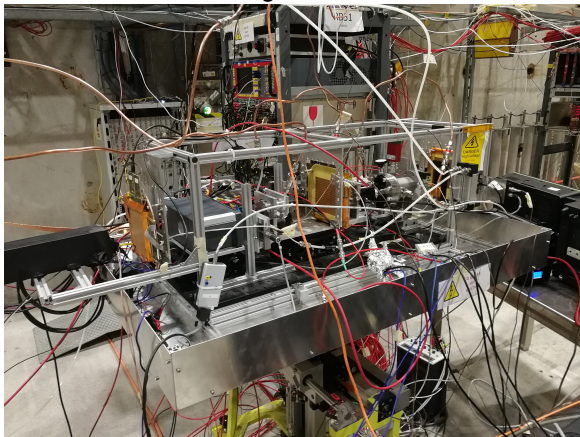
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Acknowledgments

The authors would like to thank the RD51 and PICOSEC collaborations for the possibility to participate in the May 2018 test beam.

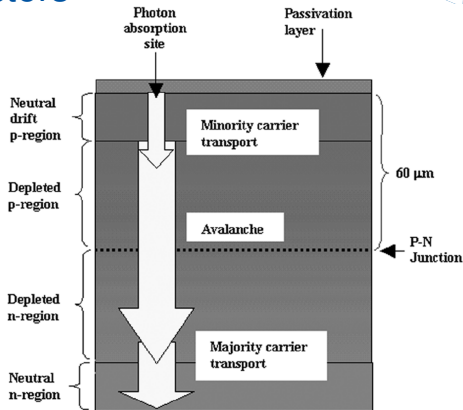
We are particularly grateful to Eraldo, Paco, and Lukas.

We would like to thank Francisco for the coating of the detectors and PCB.



Deep Diffused Avalanche Photo Detectors

- Charge multiplication
- Gain: ≈ 500
- Bias: ≈ 1800 V
- Never fully depleted
- Die dimensions: 2.8×2.8 mm² and 10×10 mm²
- Nominal active area: 2×2 mm² and 8×8 mm²
- Thickness: 230 – 280 μ m
- Custom fabrication process
- Produced by Radiation Monitoring Devices (RMD)

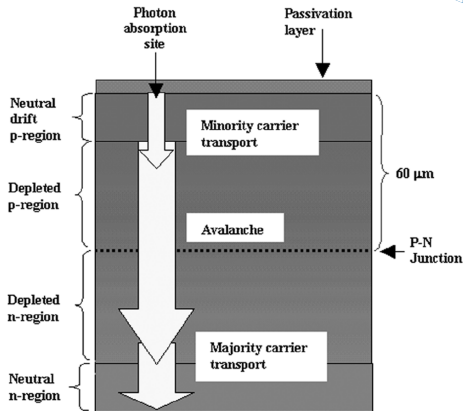
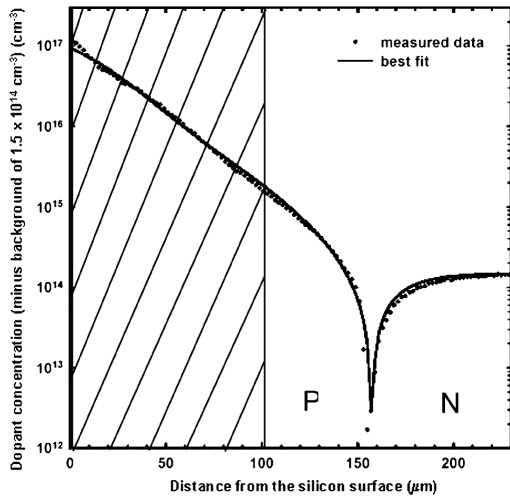


- Diffusion (non-depleted Si)
- Drift (depleted Si)
- Multiplication

M. McClish et. al. IEEE Trans. Nucl. Sci. Vol. 53, No. 5, 2006

Deep Diffused Avalanche Photo Detectors

Doping profile



- Maximum of electric field at pn-junction
- Field exceeds 200 kV/cm enabling impact ionization

M. McClish et. al. IEEE Trans. Nucl. Sci. Vol. 53, No. 5, 2006

$2 \times 2 \text{ mm}^2$ DD-APDs

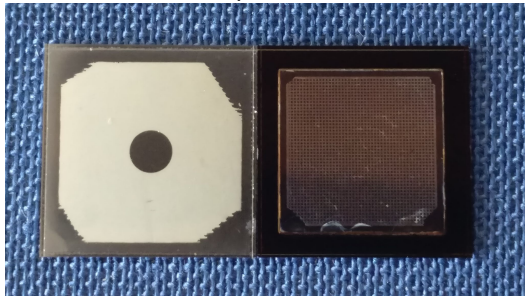


- Packaged
- Usually employed in irradiation studies

8 × 8 mm² DD-APDs

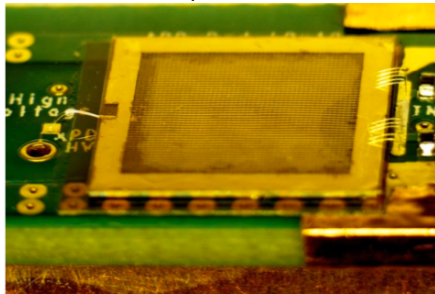
- Uniformity of response improved through metallization or mesh readout
- Baseline for timing applications

DC coupled readout



- Aluminum deposited on both sides
- Metallization on single dies at CMi-EPFL
- Studied in this beam test

AC coupled readout

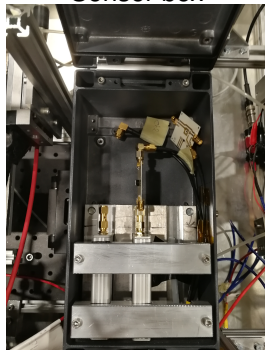


- Mesh on Kapton layer
- Sintered gold on back side
- Studied in previous beam tests ($\sigma_{\Delta t} = 19$ ps)
- See also S. White, CHEF 2013 [🔗](#)

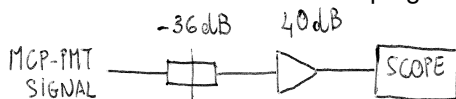
Beam Test Setup

- Sensor box placed downstream first tracking GEM
- Detectors and PCBs coated with FSC 400 to reduce discharges
- Amplifiers: CIVIDEC 2 GHz, 40 dB
- Data acquisition: Agilent 2.5 GHz, 10 Gs/s
 - Ch1: APD
 - Ch2: APD
 - Ch3: Telescope bit pattern (Trigger)
 - Ch4: MCP-PMT
- Temperature, bias, and current logged

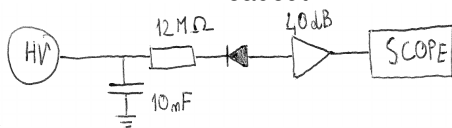
Sensor box



MCP-PMT readout and shaping

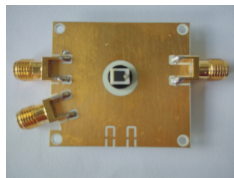


APD readout



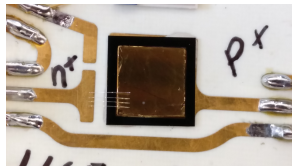
Detectors:

- 4 × Metallized $8 \times 8 \text{ mm}^2$ APDs
- 1 × Sintered gold on n-side $8 \times 8 \text{ mm}^2$ APD
- 1 × $2 \times 2 \text{ mm}^2$ APD
- 1 × LGAD (Low Gain Avalanche Detector)
- 1 × PiN diode



(Planned) Studies:

- Time resolution
- Uniformity of response
- Detection efficiency
- Dependency of time resolution and efficiency on bias voltage and position



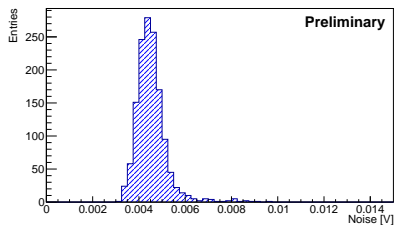
- Analysis using only oscilloscope data (for now), **no tracking info**
- Baseline subtraction, noise, and amplitude extraction
- Thresholds to be fulfilled by all channels to select event
- Cut on amplitude to exclude saturation
- Cut on rise time to exclude noise
- Calculation of Δt using CFD with interpolation between two points

Today's data: a metallized and a gold plated APD operated at 1775 V
All results shown today are PRELIMINARY

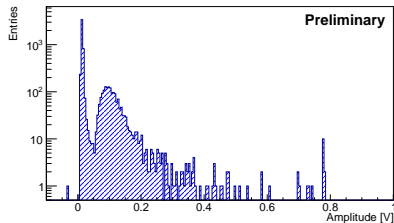
Event Selection

Run 2018-05-04_18-55-07 Metallized APD 1775 V

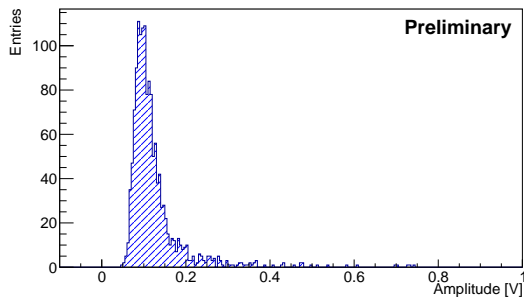
Noise of each event, around 4.5 mV



Amplitude, before cuts

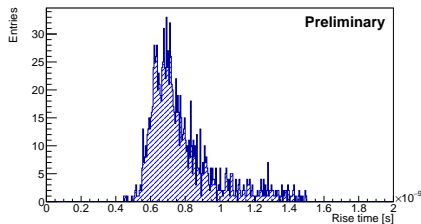


Amplitude, after cuts

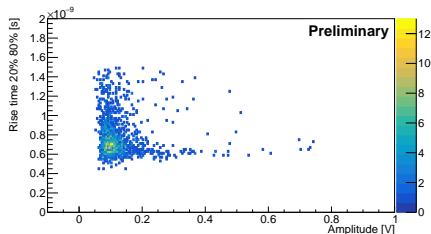


Run 2018-05-04_18-55-07

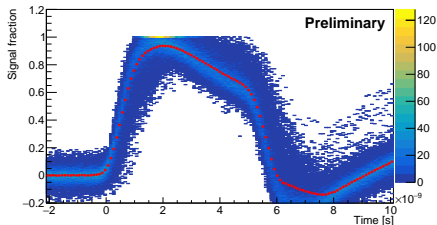
Rise Time 20-80%, cut at 1.5 ns



Rise time vs. amplitude metallized APD



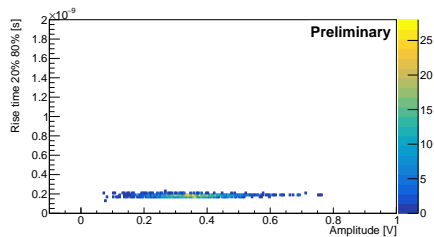
Scaled signal superimposition



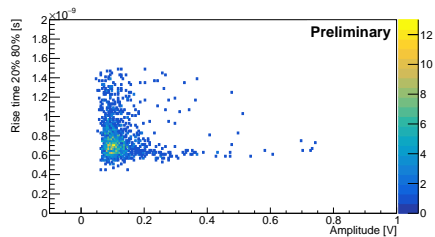
- Reflection due to bias filter at around 5 ns
- Rise time distribution and correlation with amplitude point to different signal shapes
- Possible non-uniformity of response

Run 2018-05-04_18-55-07

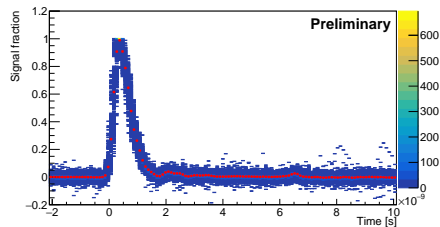
Rise time vs. amplitude MCP-PMT



Rise time vs. amplitude metallized APD



Scaled signal superimposition MCP-PMT

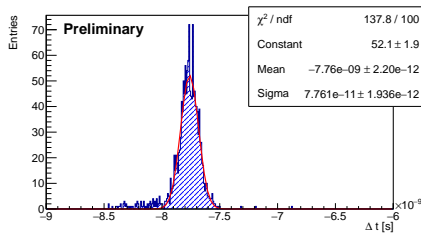


- No correlation in rise time vs. amplitude observed for MCP-PMT

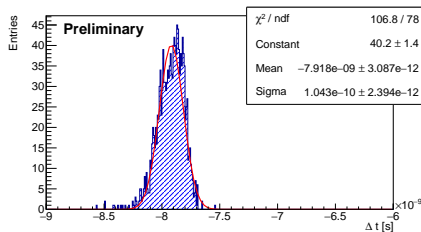
Run 2018-05-04_18-55-07

Δt MCP-PMT metallized APD, $\sigma_{\Delta t} = 77$ ps

- Timing using CFD
- APD threshold 0.2
- MCP-PMT threshold 0.5
- Time resolution worse than expected (≈ 20 ps using laser light, 0.8 MIPs, 1750 V)
- Tracking can provide an explanation



Δt MCP-PMT gold plated APD, $\sigma_{\Delta t} = 104$ ps



- First analysis of beam test data, without tracking
- Data is quite clean, DAQ worked as expected during the beam test period
- Time resolution of APDs worse than expected from laser measurement (and making an assumption on “Landau noise”) → tracking data analysis can provide explanation
- Signal properties point to non-uniformity in response → tracking data analysis

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Thank you for your attention!

Backup Material